

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. GVAR7.001A PC	APPLICATION NO. 09/880,432
	APPLICANT Givargizov, et al.	
	FILING DATE November 29, 2001	GROUP Unknown

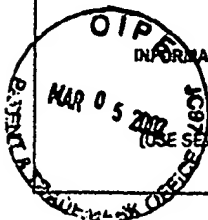
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
len	5,742,377	04/21/98	Mirna, et al.	—	—	
len	5,825,122	10/20/98	Givargizov, et al.	—	—	
len	6,308,734	10/23/01	Givargizov	—	—	

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
len	WO 98/42101	12/27/98	PCT	—	—		
len	WO 98/58225	11/18/99	PCT	—	—		

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
len	C.A. Spindt, et al., <i>Physical properties of thin-film field emission cathodes with molybdenum cones</i> , J. Appl. Phys., 47, pp. 5248-5263 (1976)
len	P. Grütter, et al., <i>Batch fabricated sensors for magnetic force microscopy</i> , Appl. Phys. Lett. 57, pp. 1820-1822 (1990)
len	D.W. Abraham, et al., <i>Lateral dopant profiling in semiconductors by force microscopy using capacitive detection</i> , J. Vac. Sci. Technol., 89, pp. 703-706 (1991)
len	K.L. Lee, et al., <i>Submicron Si trench profiling with an electron-beam fabricated atomic force microscope tip</i> , J. Vac. Sci. Technol., 89, pp. 3352-3568 (1991)
len	E.I. Givargizov, <i>Ultrasharp tips for field emission applications prepared by the vapor-liquid-solid growth technique</i> , J. Vac. Sci. Technol., 811, pp. 449-453 (1993)

EXAMINER	len NGUYEN	DATE CONSIDERED	02-24-05
*EXAMINER: INITIAL IF CITATION CONSIDERED. WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. GVAR7.001APC	APPLICATION NO. 09/880,432
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EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
LEN	C.D. Frisbie, et al., <i>Functional group imaging by chemical force microscopy</i> , Science, 265, pp. 2071-2074 (1994)
	V.A. Bykov, et al., <i>New devices and possibilities in a scanning probe microscopy</i> , in: Proc. Russian 1999 Conf. On SPM, Nizhni Novgorod, pp. 132-133 (March 1999)
	J. Browning, <i>Field emission display development and testing</i> , Proc. Of the 8th Intern. Conf. On Vacuum Microelectronics (Portland, USA), pp. 1-8 (1995)
	Y. Huang, et al., <i>Quantitative two-dimensional dopant profiling of abrupt dopant profiles by cross-sectional scanning capacitance microscopy</i> , J. Vac. Sci. Technol. A14, pp. 1168-1171 (1998)
	J.H. Hafner, et al., <i>Growth of nanotubes for probe microscopy tips</i> , Nature 398, pp. 781-782 (1998)
	P. Leitnerbach, et al., <i>Fabrication and characterization of advanced probes for magnetic force microscopy</i> , Appl. Surf. Sci., 144-145, pp. 492-498 (1999)
	L. Abelman, et al., <i>Analysis of the limits of resolution in magnetic force microscopy using EBID tips</i> , a paper presented to Intern. STM Conf., Seoul, Korea, Ext. Abstr., pp. 477-478 (1998)
	V.V. Orlov, et al., <i>An alternative working mode of SPM at surface investigations</i> , in: Proc. Russian 1999 Conf. On SPM, Nizhni Novgorod, pp. 404-410 (March 1999)
LEN	E.I. Givargizov, et al., <i>Whisker probes</i> , Ultramicroscopy 82, pp. 57-61 (2000)

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